

**FAIRCHILD**  
SEMICONDUCTOR™

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FQPF17N08

**QFET™**

## FQPF17N08

### 80V N-Channel MOSFET

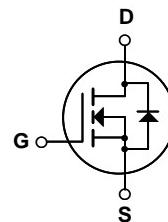
#### General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand a high energy pulse in the avalanche and commutation modes. These devices are well suited for low voltage applications such as automotive, high efficiency switching for DC/DC converters, and DC motor control.

#### Features

- 11.2A, 80V,  $R_{DS(on)} = 0.115\Omega$  @  $V_{GS} = 10$  V
- Low gate charge ( typical 12 nC)
- Low  $C_{RSS}$  ( typical 28 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating



#### Absolute Maximum Ratings

$T_C = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	FQPF17N08	Units
$V_{DSS}$	Drain-Source Voltage	80	V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ )	11.2	A
	- Continuous ( $T_C = 100^\circ\text{C}$ )	7.9	A
$I_{DM}$	Drain Current - Pulsed	(Note 1)	A
$V_{GSS}$	Gate-Source Voltage	$\pm 25$	V
$E_{AS}$	Single Pulsed Avalanche Energy	(Note 2)	mJ
$I_{AR}$	Avalanche Current	(Note 1)	A
$E_{AR}$	Repetitive Avalanche Energy	(Note 1)	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$	(Note 3)	V/ns
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ )	30	W
	- Derate above $25^\circ\text{C}$	0.2	W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +175	$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

#### Thermal Characteristics

Symbol	Parameter	Typ	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	--	5.0	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	62.5	$^\circ\text{C}/\text{W}$

## Electrical Characteristics

$T_C = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
<b>Off Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 250 \mu\text{A}$	80	--	--	V
$\Delta BV_{DSS}$ / $\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.08	--	$\text{V}/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 80 \text{ V}$ , $V_{GS} = 0 \text{ V}$	--	--	1	$\mu\text{A}$
		$V_{DS} = 64 \text{ V}$ , $T_C = 150^\circ\text{C}$	--	--	10	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 25 \text{ V}$ , $V_{DS} = 0 \text{ V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -25 \text{ V}$ , $V_{DS} = 0 \text{ V}$	--	--	-100	nA

## On Characteristics

$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$	2.0	--	4.0	V
$R_{DS(\text{on})}$	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}$ , $I_D = 5.6 \text{ A}$	--	0.088	0.115	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 30 \text{ V}$ , $I_D = 5.6 \text{ A}$ (Note 4)	--	5.13	--	S

## Dynamic Characteristics

$C_{iss}$	Input Capacitance	$V_{DS} = 25 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $f = 1.0 \text{ MHz}$	--	350	450	pF
$C_{oss}$	Output Capacitance		--	120	155	pF
$C_{rss}$	Reverse Transfer Capacitance		--	28	35	pF

## Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 40 \text{ V}$ , $I_D = 16.5 \text{ A}$ , $R_G = 25 \Omega$	--	4.8	20	ns
$t_r$	Turn-On Rise Time		--	60	130	ns
$t_{d(off)}$	Turn-Off Delay Time		--	15	40	ns
$t_f$	Turn-Off Fall Time		--	25	60	ns
$Q_g$	Total Gate Charge	$V_{DS} = 64 \text{ V}$ , $I_D = 16.5 \text{ A}$ , $V_{GS} = 10 \text{ V}$	--	12	15	nC
$Q_{gs}$	Gate-Source Charge		--	2.7	--	nC
$Q_{gd}$	Gate-Drain Charge		--	5.4	--	nC
			(Note 4, 5)			

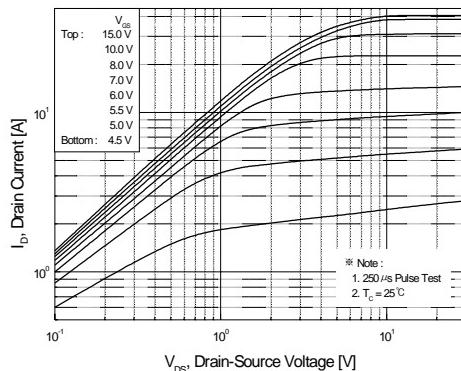
## Drain-Source Diode Characteristics and Maximum Ratings

$I_S$	Maximum Continuous Drain-Source Diode Forward Current	--	--	11.2	A	
$I_{SM}$	Maximum Pulsed Drain-Source Diode Forward Current	--	--	44.8	A	
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}$ , $I_S = 11.2 \text{ A}$	--	--	1.5	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0 \text{ V}$ , $I_S = 16.5 \text{ A}$ , $dI_F / dt = 100 \text{ A}/\mu\text{s}$	--	55	--	ns
$Q_{rr}$	Reverse Recovery Charge		--	92	--	nC

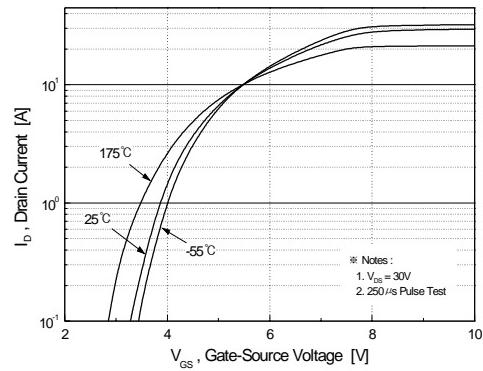
### Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2.  $L = 1.1\text{mH}$ ,  $I_{AS} = 11.2\text{A}$ ,  $V_{DD} = 25\text{V}$ ,  $R_G = 25 \Omega$ . Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 16.5\text{A}$ ,  $dI/dt \leq 300\text{A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse width  $\leq 300\mu\text{s}$ , Duty cycle  $\leq 2\%$
5. Essentially independent of operating temperature

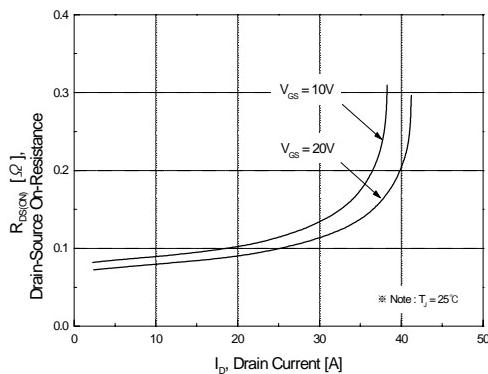
## Typical Characteristics



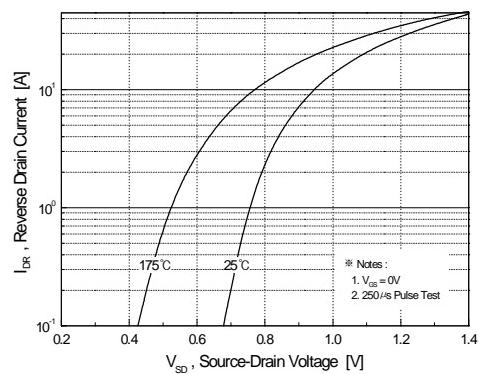
**Figure 1. On-Region Characteristics**



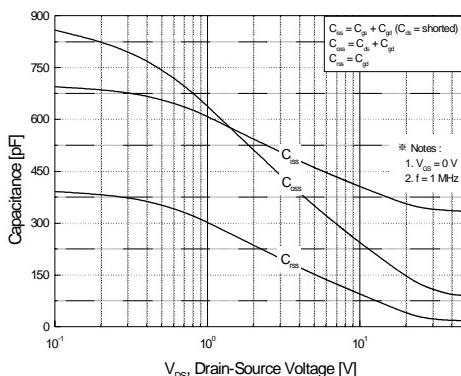
**Figure 2. Transfer Characteristics**



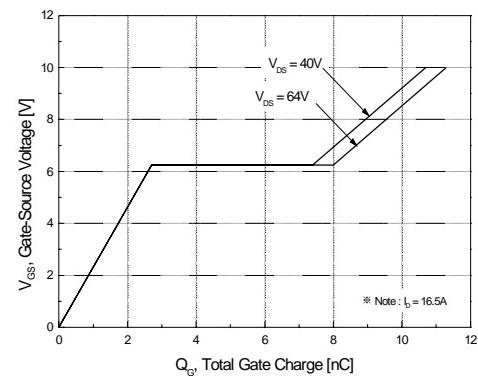
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**

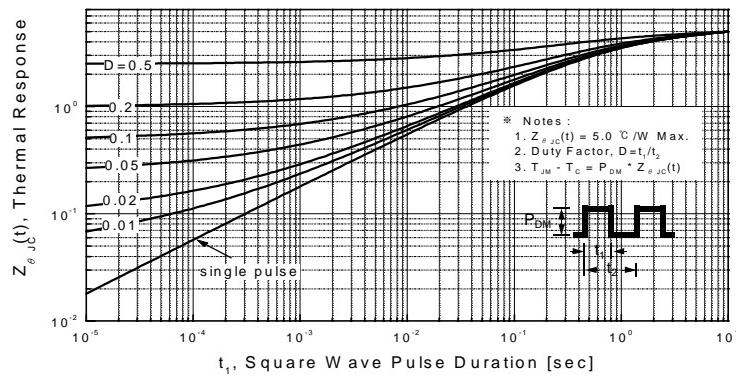
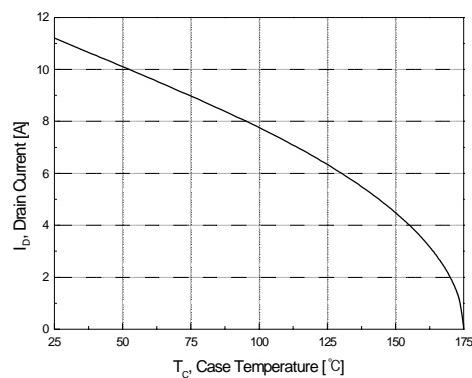
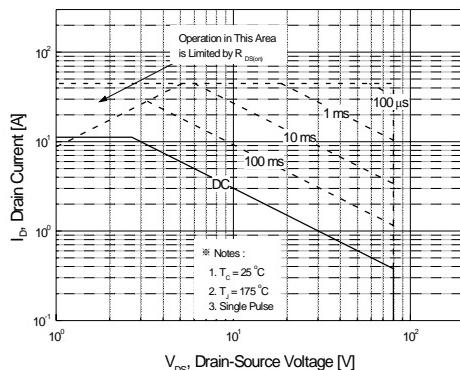
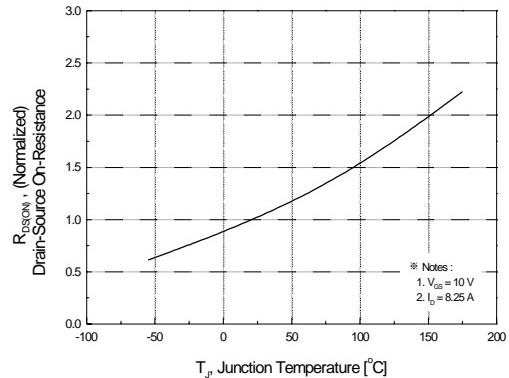
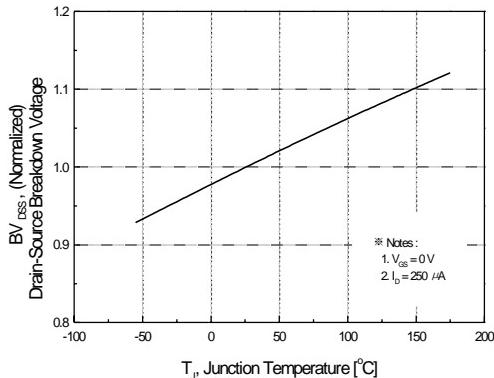


**Figure 5. Capacitance Characteristics**

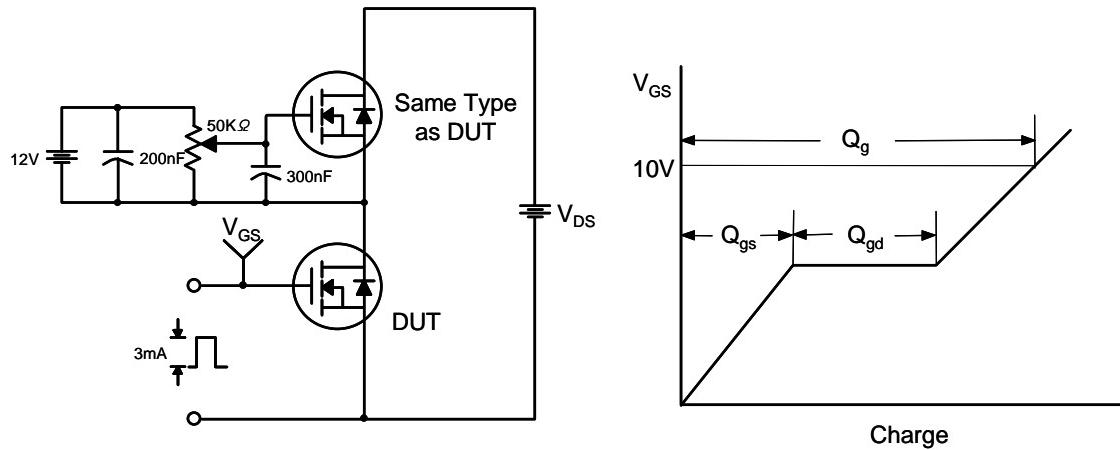


**Figure 6. Gate Charge Characteristics**

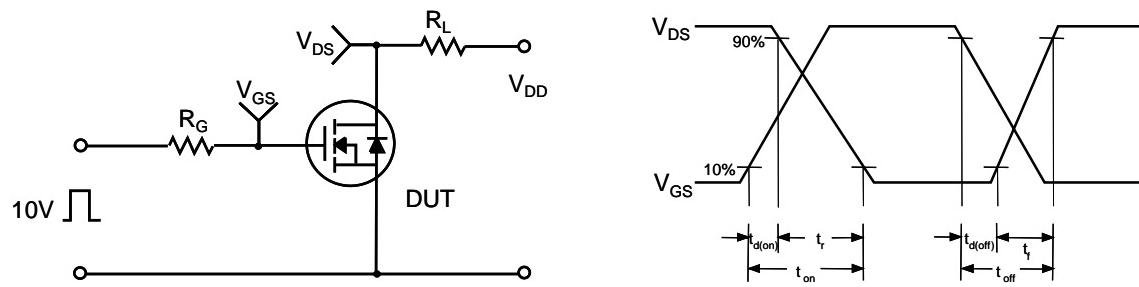
## Typical Characteristics (Continued)



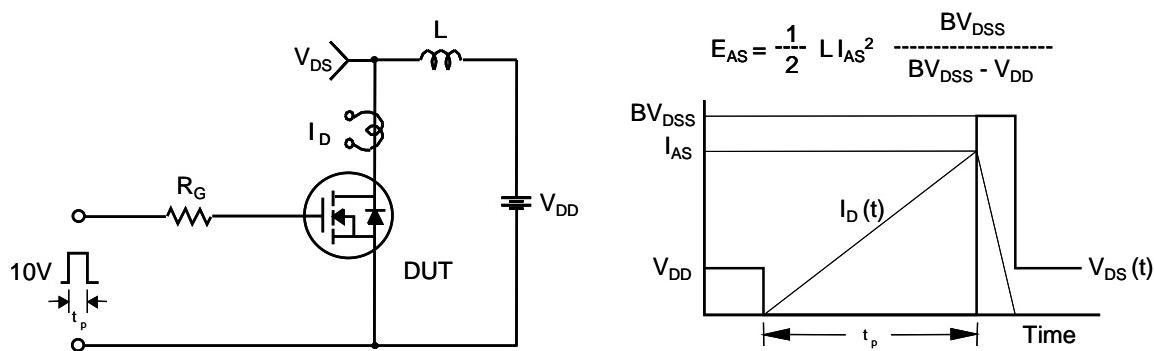
### Gate Charge Test Circuit & Waveform



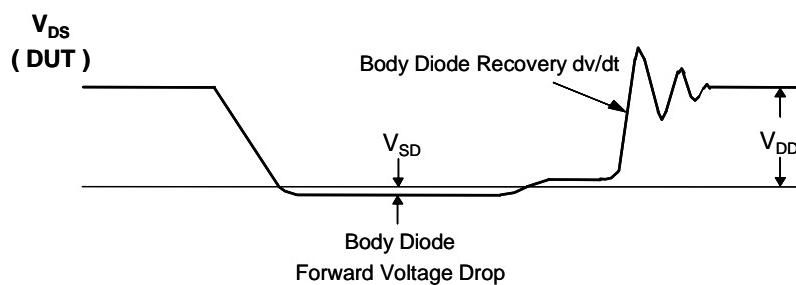
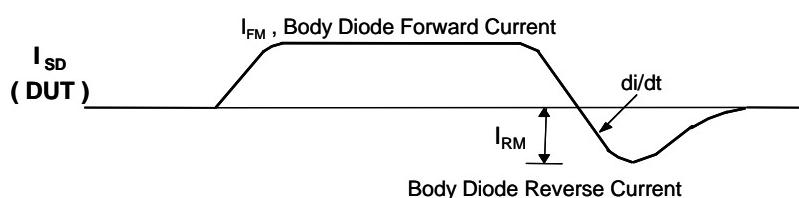
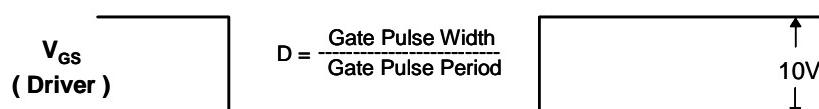
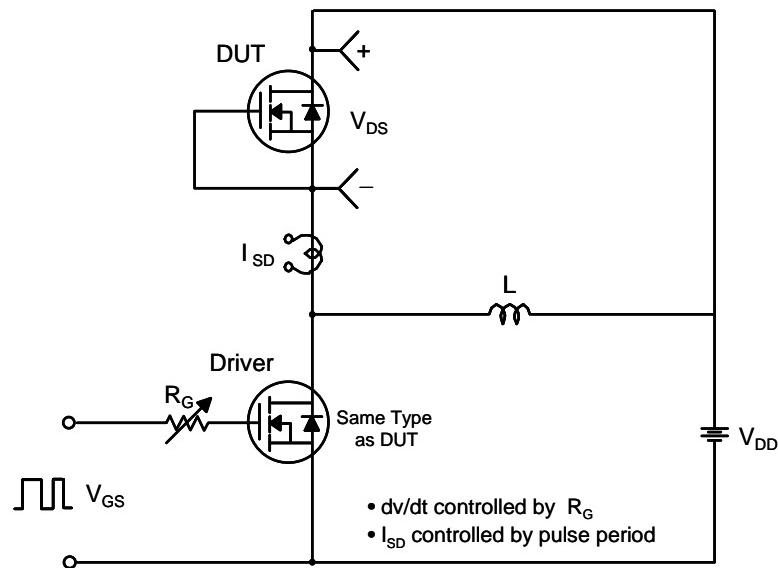
### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching Test Circuit & Waveforms

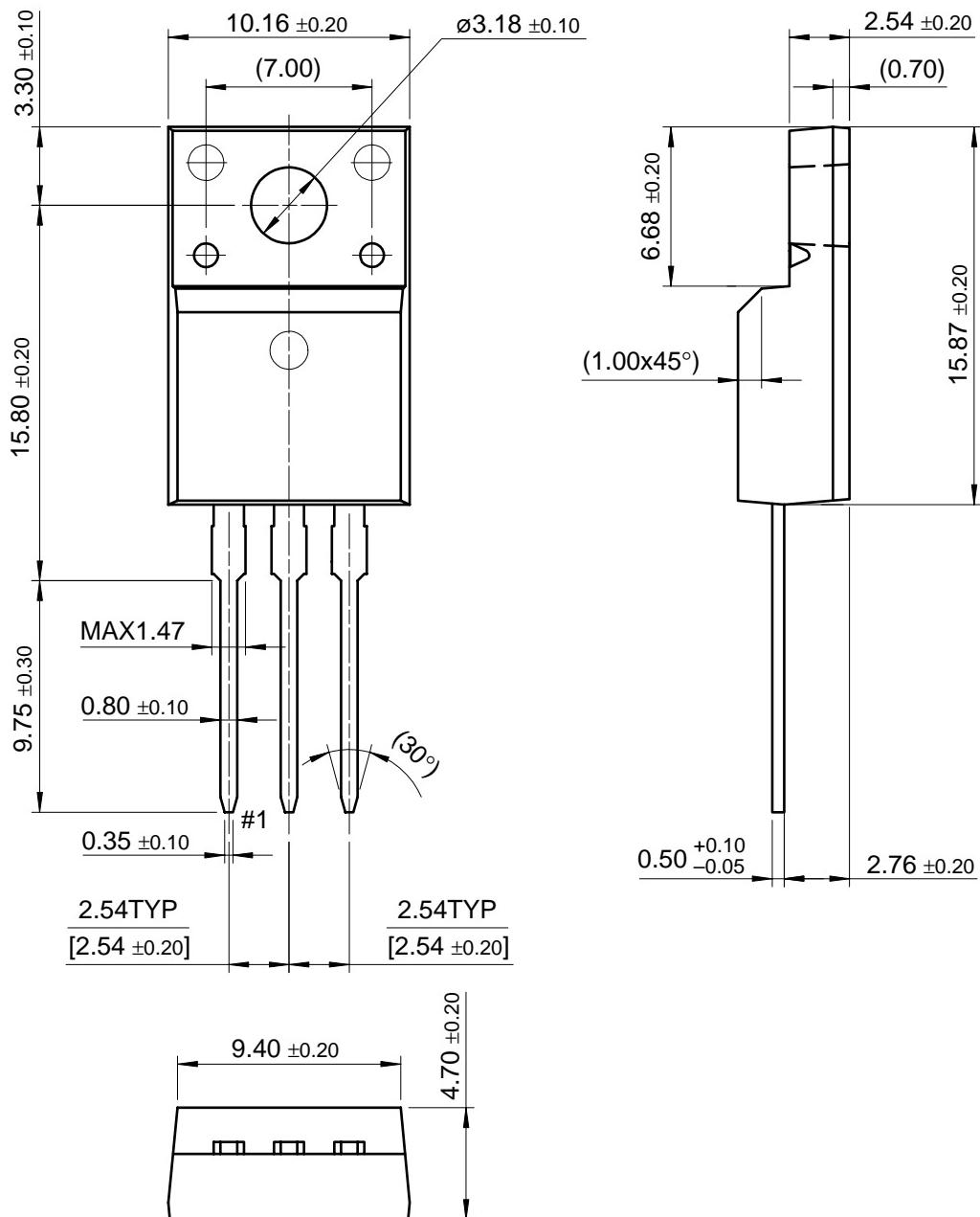


## Peak Diode Recovery dv/dt Test Circuit &amp; Waveforms



## Package Dimensions

## TO-220F



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